EE 330 Lecture 17

MOSFET Modeling

Fall 2023 Exam Schedule

- Exam 1 Friday Sept 22
- Exam 2 Friday Oct 20
- Exam 3 Friday Nov. 17

Final Monday Dec 11 12:00 – 2:00 p.m.

Prelab Announcement

There will be a pre-lab posted on the class WEB site for Lab 7

Limitations of Existing MOSFET Models



Better Model of MOSFET is Needed!

n-Channel MOSFET Operation and Model





Model in Cutoff Region

n-Channel MOSFET Operation and Model



Increase V_{GS} more

Inversion layer forms in channel Inversion layer will support current flow from D to S Channel behaves as thin-film resistor $I_D R_{CH} = V_{DS}$ $I_G = 0$ $I_B = 0$

n-Channel MOSFET Operation and Model



 I_{D} no longer linearly dependent upon V_{DS} Still termed "ohmic" or "triode" region of operation

Triode Region of Operation



For V_{DS} larger $R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_{TH}) \mu C_{OX}}$

$$I_{D} = \mu C_{OX} \frac{W}{L} \left(V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS}$$
$$I_{G} = I_{B} = 0$$

Model in Triode Region

n-Channel MOSFET Operation and Model



 $I_D = ?$ $I_G = 0$ $I_B = 0$

Increase V_{DS} even more (beyond V_{GS}-V_{TH}) Nothing much changes !! Termed "saturation"region of operation



For V_{DS} in Saturation

$$I_{D} = \frac{\mu C_{OX} W}{2L} \left(V_{GS} - V_{TH} \right)^{2}$$
$$I_{G} = I_{B} = 0$$

Model in Saturation Region



Model Parameters: { μ , V_{TH}, C_{OX}} Design Parameters : {W, L}

This is a piecewise model (not piecewise linear though) Piecewise model is continuous at transition between regions

(Deep triode special case of triode where V_{DS} is small $R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_{TH})\mu C_{OX}}$)

Note: This is the third model we have introduced for the MOSFET

Model Summary



Observations about this model (developed for V_{BS}=0):

 $I_{D} = f_{1} (V_{GS}, V_{DS})$ $I_{G} = f_{2} (V_{GS}, V_{DS})$ $I_{B} = f_{3} (V_{GS}, V_{DS})$

This is a nonlinear piecewise model characterized by the functions f_1 , f_2 , and f_3 where we have assumed that the port voltages V_{GS} and V_{DS} are the independent variables and the drain currents are the dependent variables

General Nonlinear Models



 I_1 and I_2 are 3-dimensional relationships which are often difficult to visualize

Two-dimensional representation of 3-dimensional relationships



Graphical Representation of MOS Model



 $I_{G} = I_{B} = 0$

Parabola separated triode and saturation regions and corresponds to $V_{DS}=V_{GS}-V_{TH}$

PMOS and NMOS Models



- Functional form identical, sign changes and parameter values different
- Will give details about p-channel model later

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume V_{TH}=1V and μC_{OX} =100 μ AV⁻²



Solution:

Since V_{GS} > V_{TH} , M_1 is operating in either saturation or triode region Strategy will be to guess region of operation, solve, and then verify region Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume $V_{TH}=1V$ and $\mu C_{OX}=100\mu AV^{-2}$



Solution:

Guess M₁ in saturation

 $5V = I_D 10K + V_{OUT}$ $I_D = \frac{\mu C_{OX} W}{2L} (3 - V_{TH})^2$

Required verification: $V_{DS} > V_{GS} - V_{TH}$

Can eliminate I_D between these 2 equations to obtain V_{OUT}

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume V_{TH} =1V and μC_{OX} =100 μ AV⁻²



Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume V_{TH} =1V and μC_{OX} =100 μ AV⁻² 5V

Guess M₁ in triode $5V=I_D10K+V_{OUT}$ $I_D = \frac{\mu C_{OX}W}{L} \left(3-V_{TH} - \frac{V_{DS}}{2} \right) V_{DS}$ $V_{OUT} = 5V-10K \left[\frac{100\mu AV^{-2}10\mu}{2\mu} \left(2V - \frac{V_{OUT}}{2} \right) V_{OUT} \right]$ $V_{OUT} = 5V - \left[5 \left(2V - \frac{V_{OUT}}{2} \right) V_{OUT} \right]$



Solving for V_{OUT} , obtain

 $V_{OUT} = 0.515V$

Verification: V_{DS}=V_{OUT} 0.515 <? 2V Yes!

So verification succeeds and triode region is valid

 $V_{OUT} = 0.515V$

Limitations of Existing Models



Voltage Amplifier

Model Extensions



Projections intersect –V_{DS} axis at same point, termed Early Voltage

Typical values from -20V to -200V

Usually use parameter λ instead of V_A in MOS model

Model Extensions



Model Extensions



Note: This introduces small discontinuity in model at SAT/Triode transition

Further Model Extensions

Existing model does not depend upon the bulk voltage !



Observe that changing the bulk voltage will change the electric field in the channel region ! V_{DS}



Further Model Extensions

Existing model does not depend upon the bulk voltage !

Observe that changing the bulk voltage will change the electric field in the channel region !



Changing the bulk voltage will change the thickness of the inversion layer Changing the bulk voltage will change the threshold voltage of the device

$$V_{\rm TH} = V_{\rm TH0} + \gamma \left(\sqrt{\phi - V_{\rm BS}} - \sqrt{\phi} \right)$$

 φ is the surface potential (some authors use symbol $\Phi_S)$ $\gamma\,$ is the bulk threshold

Typical Bulk Effects on Threshold Voltage for n-channel Devices

 $V_{\rm TH} = V_{\rm TH0} + \gamma \left(\sqrt{\phi} - V_{\rm BS} - \sqrt{\phi} \right)$ $\gamma \simeq 0.4 V^{1/2} \qquad \phi \simeq 0.6 V$ ′тн V_{BS} -5V

- Bulk-Diffusion Generally Reverse Biased (V_{BS}<0 or at least V_{BS}<0.3V) for n-channel
- Shift in threshold voltage with bulk voltage can be substantial
- Often V_{BS}=0

Typical Bulk Effects on Threshold Voltage for n-channel Devices



Typical Bulk Effects on Threshold Voltage for p-channel Devices



- Bulk-Diffusion Generally Reverse Biased (V_{BS}>0 or at least V_{BS}>-0.3V) for p-channel
- Same functional form as for n-channel but V_{TH0} <0
- Magnitude of threshold voltage increases with magnitude of reverse bias

Model Extension Summary





Model Parameters : { μ , C_{OX} , V_{TH0} , ϕ , γ , λ }

Design Parameters : {W,L} but only one degree of freedom W/L

Operation Regions by Applications



Most analog circuits operate in the saturation region

(basic VVR operates in triode and is an exception)

Most digital circuits operate in triode and cutoff regions and switch between these two with Boolean inputs

Model Extension (short devices)

 $I_{_{D}} = \begin{cases} 0 & V_{_{GS}} \leq V_{_{TH}} \\ \mu C_{_{OX}} \frac{W}{L} \left(V_{_{GS}} - V_{_{TH}} - \frac{V_{_{DS}}}{2} \right) V_{_{DS}} & V_{_{GS}} \geq V_{_{TH}} & V_{_{DS}} < V_{_{GS}} - V_{_{TH}} \\ \mu C_{_{OX}} \frac{W}{2L} \left(V_{_{GS}} - V_{_{TH}} \right)^2 & V_{_{GS}} \geq V_{_{TH}} & V_{_{DS}} \geq V_{_{GS}} - V_{_{TH}} \end{cases}$

As the channel length becomes very short, velocity saturation will occur in the channel and this will occur with electric fields around 2V/u. So, if a gate length is around 1u, then voltages up to 2V can be applied without velocity saturation. But, if gate length decreases and voltages are kept high, velocity saturation will occur

$$I_{_{D}} = \begin{cases} 0 & V_{_{GS}} \leq V_{_{TH}} \\ \frac{\theta_{_{2}}}{\theta_{_{1}}} \mu C_{_{OX}} \frac{W}{L} (V_{_{GS}} - V_{_{TH}})^{\frac{\alpha}{2}} V_{_{DS}} & V_{_{GS}} \geq V_{_{TH}} & V_{_{DS}} < \theta_{_{1}} (V_{_{GS}} - V_{_{TH}})^{\frac{\alpha}{2}} \\ \theta_{_{2}} \mu C_{_{OX}} \frac{W}{L} (V_{_{GS}} - V_{_{TH}})^{\alpha} & V_{_{GS}} \geq V_{_{TH}} & V_{_{DS}} \geq \theta_{_{1}} (V_{_{GS}} - V_{_{TH}})^{\frac{\alpha}{2}} \end{cases}$$

 α is the velocity saturation index, $2 \ge \alpha \ge 1$

Model Extension (short devices)

$$I_{_{D}} = \begin{cases} 0 & V_{_{GS}} \leq V_{_{TH}} \\ \frac{\theta_{_{2}}}{\theta_{_{1}}} \mu C_{_{OX}} \frac{W}{L} (V_{_{GS}} - V_{_{TH}})^{\frac{\alpha}{2}} V_{_{DS}} & V_{_{GS}} \geq V_{_{TH}} & V_{_{DS}} < \theta_{_{1}} (V_{_{GS}} - V_{_{TH}})^{\frac{\alpha}{2}} \\ \theta_{_{2}} \mu C_{_{OX}} \frac{W}{L} (V_{_{GS}} - V_{_{TH}})^{\alpha} & V_{_{GS}} \geq V_{_{TH}} & V_{_{DS}} \geq \theta_{_{1}} (V_{_{GS}} - V_{_{TH}})^{\frac{\alpha}{2}} \end{cases}$$

 α is the velocity saturation index, $2 \ge \alpha \ge 1$

No longer a square-law model (some term it an α -power or α -law model)

For long devices, α =2

Channel length modulation (λ) and bulk effects can be added to the velocity Saturation as well

Degrading of α is not an attractive limitation of the MOSFET

Be aware of existence but of little use !

(too complicated for analytical calculations, not accurate enough for simulations)

Model Extension (BSIM model)

.MODEL CN	105	SN NMOS (LEVEL	=	49	
+VERSION	=	3.1	TNOM	=	27	TOX	=	1.42E-8	
+XJ	=	1.5E-7	NCH	=	1.7E17	VTHO	=	0.629035	
+K1	=	0.8976376	K2	=	-0.09255	K3	=	24.0984767	
+K3B	=	-8.2369696	WO	=	1.041146E-8	NLX	=	1E-9	
+DVTOW	=	0	DVT1W	=	0	DVT2W	=	0	
+DVT0	=	2.7123969	DVT1	=	0.4232931	DVT2	=	-0.1403765	
+00	=	451.2322004	UA	=	3.091785E-13	UB	=	1.702517E-18	
+UC	=	1.22401E-11	VSAT	=	1.715884E5	A0	=	0.6580918	
+AGS	=	0.130484	B0	=	2.446405E-6	B1	=	5E-6	
+KETA	=	-3.043349E-3	A1	=	8.18159E-7	A2	=	0.3363058	
+RDSW	=	1.367055E3	PRWG	=	0.0328586	PRWB	=	0.0104806	
+WR	=	1	WINT	=	2.443677E-7	LINT	=	6.999776E-8	
+XL	=	1E-7	XW	=	0	DWG	=	-1.256454E-8	
+DWB	=	3.676235E-8	VOFF	=	-1.493503E-4	NFACTOR	=	1.0354201	
+CIT	=	0	CDSC	=	2.4E-4	CDSCD	=	0	
+CDSCB	=	0	ETAO	=	2.342963E-3	ETAB	=	-1.5324E-4	
+DSUB	=	0.0764123	PCLM	=	2.5941582	PDIBLC1	=	0.8187825	
+PDIBLC2	=	2.366707E-3	PDIBLCB	=	-0.0431505	DROUT	=	0.9919348	
+PSCBE1	=	6.611774E8	PSCBE2	=	3.238266E-4	PVAG	=	0	
+PRT	=	0	UTE	=	-1.5	KT1	=	-0.11	
+KT1L	=	0	KT2	=	0.022	UA1	=	4.31E-9	
+UB1	=	-7.61E-18	UC1	=	-5.6E-11	AT	=	3.3E4	
+WL	=	0	WLN	=	1	WW	=	0	
+WWN	=	1	WWL	=	0	LL	=	0	
+LLN	=	1	LW	=	0	LWN	=	1	
+LWL	=	0	CAPMOD	=	2	XPART	=	0.5	
+CGDO	=	2.32E-10	CGSO	=	2.32E-10	CGBO	=	1E-9	
+CJ	=	4.282017E-4	PB	=	0.9317787	MJ	=	0.4495867	
+CJSW	=	3.034055E-10	PBSW	=	0.8	MJSW	=	0.1713852	
+CJSWG	=	1.64E-10	PBSWG	=	0.8	MJSWG	=	0.1713852	
+CF	=	0	PVTHO	=	0.0520855	PRDSW	=	112.8875816	
+PK2	=	-0.0289036	WKETA	=	-0.0237483	LKETA	=	1.728324E-3)
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Model Errors with Different W/L Values



Binning models can improve model accuracy

BSIM Binning Model

- Bin on device sizes

- multiple BSIM models !

.MODEL C	MOSN NMOS (LEVEL	=	49
+VERSION	= 3.1	TNOM	=	27	TOX	=	1.42E-8
+XJ	= 1.5E-7	NCH	=	1.7E17	VTHO	=	0.629035
+K1	= 0.8976376	K2	=	-0.09255	КЗ	=	24.0984767
+K3B	= -8.2369696	WO	=	1.041146E-8	NLX	=	1E-9
+DVTOW	= 0	DVT1W	=	0	DVT2W	=	0
+DVT0	= 2.7123969	DVT1	=	0.4232931	DVT2	=	-0.1403765
+U0	= 451.2322004	UA	=	3.091785E-13	UB	=	1.702517E-18
+UC	= 1.22401E-11	VSAT	=	1.715884E5	A0	=	0.6580918
+AGS	= 0.130484	B0	=	2.446405E-6	B1	=	5E-6
+KETA	= -3.043349E-3	A1	=	8.18159E-7	A2	=	0.3363058
+RDSW	= 1.367055E3	PRWG	=	0.0328586	PRWB	=	0.0104806
+WR	= 1	WINT	=	2.443677E-7	LINT	=	6.999776E-8
+XL	= 1E-7	XW	=	0	DWG	=	-1.256454E-8
+DWB	= 3.676235E-8	VOFF	=	-1.493503E-4	NFACTOR	=	1.0354201
+CIT	= 0	CDSC	=	2.4E-4	CDSCD	=	0
+CDSCB	= 0	ETAO	=	2.342963E-3	ETAB	=	-1.5324E-4
+DSUB	= 0.0764123	PCLM	=	2.5941582	PDIBLC1	=	0.8187825
+PDIBLC2	= 2.366707E-3	PDIBLCB	=	-0.0431505	DROUT	=	0.9919348
+PSCBE1	= 6.611774E8	PSCBE2	=	3.238266E-4	PVAG	=	0
+PRT	= 0	UTE	=	-1.5	KT1	=	-0.11
+KT1L	= 0	KT2	=	0.022	UA1	=	4.31E-9
+UB1	= -7.61E-18	UC1	=	-5.6E-11	AT	=	3.3E4
+WL	= 0	WLN	=	1	WW	=	0
+WWN	= 1	WWL	=	0	LL	=	0
+LLN	= 1	LW	=	0	LWN	=	1
+LWL	= 0	CAPMOD	=	2	XPART	=	0.5
+CGDO	= 2.32E-10	CGSO	=	2.32E-10	CGBO	=	1E-9
+CJ	= 4.282017E-4	PB	=	0.9317787	MJ	=	0.4495867
+CJSW	= 3.034055E-10	PBSW	=	0.8	MJSW	=	0.1713852
+CJSWG	= 1.64E-10	PBSWG	=	0.8	MJSWG	=	0.1713852
+CF	= 0	PVTHO	=	0.0520855	PRDSW	=	112.8875816
+PK2	= -0.0289036	WKETA	=	-0.0237483	LKETA	=	1.728324E-3

* With 32 bins, this model has 3040 model parameters !

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Model Changes with Process Variations

(n-ch characteristics shown)



Corner models can improve model accuracy

BSIM Corner Models with Binning

- Often 4 corners in addition to nominal TT, FF, FS, SF, and SS

- bin on device sizes

.MODEL CN	MOSN NMOS (LEVEL	= 49
+VERSION	= 3.1	TNOM	= 27	TOX	= 1.42E - 8
+XJ	= 1.5E-7	NCH	= 1.7E17	VTHO	= 0.629035
+K1	= 0.8976376	K2	= -0.09255	КЗ	= 24.0984767
+K3B	= -8.2369696	WO	= 1.041146E-8	NLX	= 1E-9
+DVTOW	= 0	DVT1W	= 0	DVT2W	= 0
+DVT0	= 2.7123969	DVT1	= 0.4232931	DVT2	= -0.1403765
+00	= 451.2322004	UA	= 3.091785E-13	UB	= 1.702517E-18
+UC	= 1.22401E-11	VSAT	= 1.715884E5	AO	= 0.6580918
+AGS	= 0.130484	B0	= 2.446405E-6	B1	= 5E-6
+KETA	= -3.043349E-3	A1	= 8.18159E-7	A2	= 0.3363058
+RDSW	= 1.367055E3	PRWG	= 0.0328586	PRWB	= 0.0104806
+WR	= 1	WINT	= 2.443677E-7	LINT	= 6.999776E-8
+XL	= 1E-7	XW	= 0	DWG	= -1.256454E-8
+DWB	= 3.676235E-8	VOFF	= -1.493503E-4	NFACTOR	= 1.0354201
+CIT	= 0	CDSC	= 2.4E-4	CDSCD	= 0
+CDSCB	= 0	ETA0	= 2.342963E-3	ETAB	= -1.5324E-4
+DSUB	= 0.0764123	PCLM	= 2.5941582	PDIBLC1	= 0.8187825
+PDIBLC2	= 2.366707E-3	PDIBLCB	= -0.0431505	DROUT	= 0.9919348
+PSCBE1	= 6.611774E8	PSCBE2	= 3.238266E-4	PVAG	= 0
+DELTA	= 0.01	RSH	= 83.5	MOBMOD	= 1
+PRT	= 0	UTE	= -1.5	KT1	= -0.11
+KT1L	= 0	KT2	= 0.022	UA1	= 4.31E-9
+UB1	= -7.61E-18	UC1	= -5.6E-11	AT	= 3.3E4
+WL	= 0	WLN	= 1	WW	= 0
+WWN	= 1	WWL	= 0	LL	= 0
+LLN	= 1	LW	= 0	LWN	= 1
+LWL	= 0	CAPMOD	= 2	XPART	= 0.5
+CGDO	= 2.32E - 10	CGSO	= 2.32E - 10	CGBO	= 1E-9
+CJ	= 4.282017E-4	PB	= 0.9317787	MJ	= 0.4495867
+CJSW	= 3.034055E-10	PBSW	= 0.8	MJSW	= 0.1713852
+CJSWG	= 1.64E - 10	PBSWG	= 0.8	MJSWG	= 0.1713852
+CF	= 0	PVTH0	= 0.0520855	PRDSW	= 112.8875816
+PK2	= -0.0289036	WKETA	= -0.0237483	LKETA	= 1.728324E-3
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With 32 size bins and 4 corners, this model has 15,200 model parameters !

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How many models of the MOSFET do we have?

Switch-level model (2)

Square-law model

Square-law model (with λ and bulk additions)

 α -law model (with λ and bulk additions)

BSIM model

BSIM model (with binning extensions)

BSIM model (with binning extensions and process corners)

The Modeling Challenge





 $I_{D} = f_{1} (V_{GS}, V_{DS})$ $I_{G} = f_{2} (V_{GS}, V_{DS})$ $I_{B} = f_{3} (V_{GS}, V_{DS})$

Difficult to obtain analytical functions that accurately fit actual devices over bias, size, and process variations

Model Status



In the next few slides, the models we have developed will be listed and reviewed

- Square-law Model
- Switch-level Models
- Extended Square-law model
- Short-channel model
- BSIM Model
- BSIM Binning Model
- Corner Models

Square-Law Model



$$\begin{split} I_{\scriptscriptstyle D} = \begin{cases} 0 & V_{\scriptscriptstyle GS} \leq V_{\scriptscriptstyle TH} \\ \mu C_{\scriptscriptstyle OX} \, \frac{W}{L} \bigg(V_{\scriptscriptstyle GS} - V_{\scriptscriptstyle TH} - \frac{V_{\scriptscriptstyle DS}}{2} \bigg) V_{\scriptscriptstyle DS} & V_{\scriptscriptstyle GS} \geq V_{\scriptscriptstyle TH} & V_{\scriptscriptstyle DS} < V_{\scriptscriptstyle GS} - V_{\scriptscriptstyle TH} \\ \mu C_{\scriptscriptstyle OX} \, \frac{W}{2L} \big(V_{\scriptscriptstyle GS} - V_{\scriptscriptstyle TH} \big)^2 & V_{\scriptscriptstyle GS} \geq V_{\scriptscriptstyle TH} & V_{\scriptscriptstyle DS} \geq V_{\scriptscriptstyle GS} - V_{\scriptscriptstyle TH} \end{cases} \end{split}$$

Model Parameters : $\{\mu, C_{OX}, V_{TH0}\}$ Design Parameters : $\{W, L\}$ but only one degree of freedom W/L

Switch-Level Models



 C_{GS} and R_{SW} dependent upon device sizes and process

For minimum-sized devices in a 0.5u process

$$C_{GS} \cong 1.5 fF$$
 $R_{sw} \cong$ $\begin{array}{c} 2K\Omega \ n-channel \\ 6K\Omega \ p-channel \end{array}$

Considerable emphasis will be placed upon device sizing to manage C_{GS} and R_{SW}

Model Parameters : {C_{GS}, R_{SW}}

Extended Square-Law Model



Model Parameters : { μ , C_{OX} , V_{TH0} , ϕ , γ , λ }

Design Parameters : {W,L} but only one degree of freedom W/L

Short-Channel Model

$$\mathbf{I}_{_{\mathrm{D}}} = \begin{cases} \mathbf{0} & \mathbf{V}_{_{\mathrm{GS}}} \leq \mathbf{V}_{_{\mathrm{TH}}} \\ \frac{\theta_{_{2}}}{\theta_{_{1}}} \mu \mathbf{C}_{_{\mathrm{OX}}} \frac{W}{L} \left(\mathbf{V}_{_{\mathrm{GS}}} - \mathbf{V}_{_{\mathrm{TH}}}\right)^{\frac{\alpha}{2}} \mathbf{V}_{_{\mathrm{DS}}} & \mathbf{V}_{_{\mathrm{GS}}} \geq \mathbf{V}_{_{TH}} \quad \mathbf{V}_{_{\mathrm{DS}}} < \theta_{_{1}} \left(\mathbf{V}_{_{\mathrm{GS}}} - \mathbf{V}_{_{TH}}\right)^{\frac{\alpha}{2}} \\ \theta_{_{2}} \mu \mathbf{C}_{_{\mathrm{OX}}} \frac{W}{L} \left(\mathbf{V}_{_{\mathrm{GS}}} - \mathbf{V}_{_{\mathrm{TH}}}\right)^{\alpha} & \mathbf{V}_{_{\mathrm{GS}}} \geq \mathbf{V}_{_{\mathrm{TH}}} \quad \mathbf{V}_{_{\mathrm{DS}}} \geq \theta_{_{1}} \left(\mathbf{V}_{_{\mathrm{GS}}} - \mathbf{V}_{_{TH}}\right)^{\frac{\alpha}{2}} \end{cases}$$

 α is the velocity saturation index, $2 \ge \alpha \ge 1$

Channel length modulation (λ) and bulk effects can be added to the velocity Saturation as well

BSIM model

.MODEL CN	MOSN NMOS (LEVEL	=	49	
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+K3B	= -8.2369696	WO	=	1.041146E-8	NLX	=	1E-9	
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+DVT0	= 2.7123969	DVT1	=	0.4232931	DVT2	=	-0.1403765	
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+DSUB	= 0.0764123	PCLM	=	2.5941582	PDIBLC1	=	0.8187825	
+PDIBLC2	= 2.366707E-3	PDIBLCB	=	-0.0431505	DROUT	=	0.9919348	
+PSCBE1	= 6.611774E8	PSCBE2	=	3.238266E-4	PVAG	=	0	
	- 0	UTE	_	-15	K T1	_	-0 11	
+FRI +KT1T	- 0	KLC KLC	_	0 022	1121	_	4 31F-9	
+IIB1	= -7 61E - 18	IIC1	_	-5 6E-11	ΔT	_	3 384	
+WT.	= 0	WT.N	_	1	WW	_	0	
+WWN	= 1	WWT.	_	1 0	LT.	_	0	
+T.T.N	= 1	T.W	=	0	T.WN	=	1	
+T.WT.	= 0	CAPMOD	=	2	XPART	=	0.5	
+CGDO	= 2.32E - 10	CGSO	=	- 2.32E-10	CGBO	=	1E-9	
+CJ	= 4.282017E-4	PB	=	0.9317787	M.T	=	0.4495867	
+CJSW	= 3.034055E-10	PBSW	=	0.8	MJSW	=	0.1713852	
+CJSWG	= 1.64E - 10	PBSWG	=	0.8	MJSWG	=	0.1713852	
+CF	= 0	PVTHO	=	0.0520855	PRDSW	=	112.8875816	
+PK2	= -0.0289036	WKETA	=	-0.0237483	LKETA	=	1.728324E-3)
*	5.0205000							'

Note this model has 95 model parameters !

BSIM Binning Model

- Bin on device sizes

- multiple BSIM models !

.MODEL C	MOSN NMOS (LEVEL	=	49
+VERSION	= 3.1	TNOM	=	27	TOX	=	1.42E-8
+XJ	= 1.5E-7	NCH	=	1.7E17	VTHO	=	0.629035
+K1	= 0.8976376	K2	=	-0.09255	КЗ	=	24.0984767
+K3B	= -8.2369696	WO	=	1.041146E-8	NLX	=	1E-9
+DVTOW	= 0	DVT1W	=	0	DVT2W	=	0
+DVT0	= 2.7123969	DVT1	=	0.4232931	DVT2	=	-0.1403765
+U0	= 451.2322004	UA	=	3.091785E-13	UB	=	1.702517E-18
+UC	= 1.22401E-11	VSAT	=	1.715884E5	A0	=	0.6580918
+AGS	= 0.130484	B0	=	2.446405E-6	B1	=	5E-6
+KETA	= -3.043349E-3	A1	=	8.18159E-7	A2	=	0.3363058
+RDSW	= 1.367055E3	PRWG	=	0.0328586	PRWB	=	0.0104806
+WR	= 1	WINT	=	2.443677E-7	LINT	=	6.999776E-8
+XL	= 1E-7	XW	=	0	DWG	=	-1.256454E-8
+DWB	= 3.676235E-8	VOFF	=	-1.493503E-4	NFACTOR	=	1.0354201
+CIT	= 0	CDSC	=	2.4E-4	CDSCD	=	0
+CDSCB	= 0	ETAO	=	2.342963E-3	ETAB	=	-1.5324E-4
+DSUB	= 0.0764123	PCLM	=	2.5941582	PDIBLC1	=	0.8187825
+PDIBLC2	= 2.366707E-3	PDIBLCB	=	-0.0431505	DROUT	=	0.9919348
+PSCBE1	= 6.611774E8	PSCBE2	=	3.238266E-4	PVAG	=	0
+PRT	= 0	UTE	=	-1.5	KT1	=	-0.11
+KT1L	= 0	KT2	=	0.022	UA1	=	4.31E-9
+UB1	= -7.61E-18	UC1	=	-5.6E-11	AT	=	3.3E4
+WL	= 0	WLN	=	1	WW	=	0
+WWN	= 1	WWL	=	0	LL	=	0
+LLN	= 1	LW	=	0	LWN	=	1
+LWL	= 0	CAPMOD	=	2	XPART	=	0.5
+CGDO	= 2.32E-10	CGSO	=	2.32E-10	CGBO	=	1E-9
+CJ	= 4.282017E-4	PB	=	0.9317787	MJ	=	0.4495867
+CJSW	= 3.034055E-10	PBSW	=	0.8	MJSW	=	0.1713852
+CJSWG	= 1.64E-10	PBSWG	=	0.8	MJSWG	=	0.1713852
+CF	= 0	PVTHO	=	0.0520855	PRDSW	=	112.8875816
+PK2	= -0.0289036	WKETA	=	-0.0237483	LKETA	=	1.728324E-3

* With 32 bins, this model has 3040 model parameters !

)

BSIM Corner Models

- Often 4 corners in addition to nominal TT, FF, FS, SF, and SS

- five different BSIM models !

.MODEL C	MOSN NMOS (LEVEL	= 49	
+VERSION	= 3.1	TNOM	= 27	TOX	= 1.42E - 8	TT: typical-typical
+XJ	= 1.5E-7	NCH	= 1.7E17	VTHO	= 0.629035	
+K1	= 0.8976376	K2	= -0.09255	КЗ	= 24.0984767	FF: fast h, fast p
+K3B	= -8.2369696	WO	= 1.041146E-8	NLX	= 1E-9	FS: fast n. slow p
+DVTOW	= 0	DVT1W	= 0	DVT2W	= 0	CEL alayy n faat n
+DVT0	= 2.7123969	DVT1	= 0.4232931	DVT2	= -0.1403765	SF: Slow h, last p
+U0	= 451.2322004	UA	= 3.091785E-13	UB	= 1.702517E-18	SS: slow n. slow p
+UC	= 1.22401E-11	VSAT	= 1.715884E5	A0	= 0.6580918	
+AGS	= 0.130484	B0	= 2.446405E-6	B1	= 5E-6	
+KETA	= -3.043349E-3	A1	= 8.18159E-7	A2	= 0.3363058	
+RDSW	= 1.367055E3	PRWG	= 0.0328586	PRWB	= 0.0104806	
+WR	= 1	WINT	= 2.443677E-7	LINT	= 6.999776E-8	
+XL	= 1E-7	XW	= 0	DWG	= -1.256454E-8	
+DWB	= 3.676235E-8	VOFF	= -1.493503E-4	NFACTOR	= 1.0354201	
+CIT	= 0	CDSC	= 2.4E-4	CDSCD	= 0	
+CDSCB	= 0	ETAO	= 2.342963E-3	ETAB	= -1.5324E-4	
+DSUB	= 0.0764123	PCLM	= 2.5941582	PDIBLC1	= 0.8187825	
+PDIBLC2	= 2.366707E-3	PDIBLCB	= -0.0431505	DROUT	= 0.9919348	
+PSCBE1	= 6.611774E8	PSCBE2	= 3.238266E-4	PVAG	= 0	
+DET.TA	= 0.01	RSH	= 83.5	MOBMOD	= 1	
+PRT	= 0	UTE	= -1.5	KT1	= -0.11	
+KT1L	= 0	KT2	= 0.022	UA1	= 4.31E-9	
+UB1	= -7.61E - 18	UC1	= -5.6E-11	AT	= 3.3E4	
+WL	= 0	WLN	= 1	WW	= 0	
+WWN	= 1	WWL	= 0	LL	= 0	
+LLN	= 1	LW	= 0	LWN	= 1	
+LWL	= 0	CAPMOD	= 2	XPART	= 0.5	
+CGDO	= 2.32E - 10	CGSO	= 2.32E - 10	CGBO	= 1E-9	
+CJ	= 4.282017E-4	PB	= 0.9317787	MJ	= 0.4495867	
+CJSW	= 3.034055E-10	PBSW	= 0.8	MJSW	= 0.1713852	
+CJSWG	= 1.64E - 10	PBSWG	= 0.8	MJSWG	= 0.1713852	
+CF	= 0	PVTH0	= 0.0520855	PRDSW	= 112.8875816	
+PK2	= -0.0289036	WKETA	= -0.0237483	LKETA	= 1.728324E-3)
*						

With 4 corners, this model has 475 model parameters !

Hierarchical Model Comparisons



Corner Models



Applicable at any level in model hierarchy (same model, different parameters) Often 4 corners (FF, FS, SF, SS) used but sometimes many more

Designers must provide enough robustness so good yield at all corners



Stay Safe and Stay Healthy !

End of Lecture 17